


<b>Search Notes</b>  	<b>Application/Control No.</b>  10564154	<b>Applicant(s)/Patent Under Reexamination</b>  ASAKAWA ET AL.
	<b>Examiner</b>  David E Bochna	<b>Art Unit</b>  3679

SEARCHED			
Class	Subclass	Date	Examiner
285	249, 3, 332.1, 4	7/8/08	DB

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner